

**Notice of References Cited**

Application/Control No.

09/893,676

Applicant(s)/Patent Under  
Reexamination  
SON ET AL.

Examiner

Jennifer T Nguyen

Art Unit

2674

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,552,704	04-2003	Zavracky et al.	345/88
	B	US-5,666,133	09-1997	Matsuo et al.	345/100
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hasegawa et al. Pub. No. US 2001/0011979
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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